

Notice of References Cited

Application/Control No.

09/716,734

Applicant(s)/Patent Under
Reexamination
CHAN ET AL.

Examiner

Alexander O Williams

Art Unit

2826

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2001/0008776 A1	07-2001	Lai et al.	438/106
	B	US-2002/0195270 A1	12-2002	Okubora et al.	174/260
	C	US-5,424,573	06-1995	Kato et al.	257/431
	D	US-2002/0175421 B1	11-2002	Kimura, Naoto	257/778
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	08-250652	09-1996	Japan	Degani et al.	
	O	62-281435	12-1987	Japan	Otsuka et al.	29/827
	P	60-154648	08-1985	Japan	Shirai et al.	257/796
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.